

# Normally – OFF Silicon Carbide Junction Transistor

$V_{DS}$	=	1200 V
$V_{DS(ON)}$	=	1.4 V
$I_D$	=	20 A
$R_{\text{DS(ON)}}$	=	70 mΩ

#### **Features**

- 175 °C maximum operating temperature
- Temperature independent switching performance
- Gate oxide free SiC switch
- Suitable for connecting an anti-parallel diode
- · Positive temperature coefficient for easy paralleling
- · Low gate charge
- · Low intrinsic capacitance

#### **Package**

RoHS Compliant





**TO-247AB** 

#### **Advantages**

- Low switching losses
- · Higher efficiency
- High temperature operation
- · High short circuit withstand capability

## **Applications**

- Down Hole Oil Drilling, Geothermal Instrumentation
- Hybrid Electric Vehicles (HEV)
- Solar Inverters
- Switched-Mode Power Supply (SMPS)
- Power Factor Correction (PFC)
- Induction Heating
- Uninterruptible Power Supply (UPS)
- Motor Drives

#### Maximum Ratings unless otherwise specified

Parameter	Symbol	Conditions	Values	Unit
Drain – Source Voltage	V <sub>DS</sub>	V <sub>GS</sub> = 0 V	1200	V
Continuous Drain Current	I <sub>D</sub>	T <sub>C,MAX</sub> = 95 °C	20	Α
Gate Peak Current	I <sub>GM</sub>		10	Α
Turn-Off Safe Operating Area	RBSOA	$T_{VJ}$ = 175 °C, $I_{G}$ = 1 A, Clamped Inductive Load	$I_{D,max} = 20$ @ $V_{DS} \le V_{DSmax}$	А
Short Circuit Safe Operating Area	SCSOA	$T_{VJ}$ = 175 °C, $I_G$ = 1 A, $V_{DS}$ = 800 V, Non Repetitive	20	μs
Reverse Gate – Source Voltage	$V_{SG}$	·	30	V
Reverse Drain – Source Voltage	$V_{SD}$		25	V
Power Dissipation	P <sub>tot</sub>	T <sub>C</sub> = 95 °C	151	W
Storage Temperature	$T_{stg}$		-55 to 175	°C

## Electrical Characteristics at T<sub>i</sub> = 175 °C, unless otherwise specified

Double to the second se	Comple ed	Conditions	Values		1114	
Parameter	Symbol	Conditions -	min.	typ.	max.	Unit
On Characteristics						
		I <sub>D</sub> = 20 A, I <sub>G</sub> = 400 mA, T <sub>j</sub> = 25 °C		1.4		
Drain – Source On Voltage	$V_{DS(ON)}$	$I_D = 20 \text{ A}, I_G = 800 \text{ mA}, T_j = 125 ^{\circ}\text{C}$		1.6		V
_	, ,	$I_D = 20 \text{ A}, I_G = 1600 \text{ mA}, T_j = 175 °C$		2.2		
		$I_D = 20 \text{ A}, I_G = 400 \text{ mA}, T_j = 25 \text{ °C}$		70		
Drain – Source On Resistance	R <sub>DS(ON)</sub>	$I_D = 20 \text{ A}, I_G = 800 \text{ mA}, T_j = 125 ^{\circ}\text{C}$		80		mΩ
	, ,	$I_D = 20 \text{ A}, I_G = 1600 \text{ mA}, T_j = 175 °C$		110		
Cata Familiard Valtage	$V_{GS(FWD)}$	$I_G = 500 \text{ mA}, T_j = 25 ^{\circ}\text{C}$		3.3		V
Gate Forward Voltage		$I_G = 500 \text{ mA}, T_j = 175 ^{\circ}\text{C}$		3.1		V
DC Current Gain	o	$V_{DS} = 5 \text{ V}, I_{D} = 20 \text{ A}, T_{i} = 25 ^{\circ}\text{C}$		TBD		
	β	$V_{DS} = 5 \text{ V}, I_D = 20 \text{ A}, T_j = 175 °C$		TBD		
Off Characteristics						
		$V_R = 1200 \text{ V}, V_{GS} = 0 \text{ V}, T_j = 25 ^{\circ}\text{C}$		1.1		
Drain Leakage Current	I <sub>DSS</sub>	$V_R = 1200 \text{ V}, V_{GS} = 0 \text{ V}, T_j = 125 \text{ °C}$		1.6		μΑ
-		$V_R = 1200 \text{ V}, V_{GS} = 0 \text{ V}, T_j = 175 ^{\circ}\text{C}$		2.1		·
Gate Leakage Current	lec.	V <sub>SG</sub> = 20 V, T <sub>i</sub> = 25 °C		20		nA



Electrical Characteristics at  $T_j$  = 175 °C, unless otherwise specified

Parameter	Symbol	Conditions		Values		Unit
Parameter	Symbol	Conditions	min.	typ.	max.	Unit
Capacitance Characteristics						
Gate-Source Capacitance	C <sub>qs</sub>	V <sub>GS</sub> = 0 V, f = 1 MHz		tbd		pF
Input Capacitance	C <sub>iss</sub>	$V_{GS} = 0 \text{ V}, V_{D} = 1 \text{ V}, f = 1 \text{ MHz}$		tbd		pF
Reverse Transfer/Output Capacitance	$C_{rss}/C_{oss}$	$V_D = 1 V, f = 1 MHz$		tbd		pF
Switching Characteristics						
Turn On Delay Time	t <sub>d(on)</sub>			tbd		ns
Rise Time	t <sub>r</sub>	$V_{DD} = 800 \text{ V}, I_D = 20 \text{ A},$		tbd		ns
Turn Off Delay Time	$t_{d(off)}$	$R_{G(on)} = R_{G(off)} = 44 \Omega,$ $V_{GS} = -8/15 \text{ V, L} = 1.1 \text{ mH,}$		tbd		ns
Fall Time	t <sub>f</sub>	FWD = GB40SLT12,		tbd		ns
Turn-On Energy Per Pulse	E <sub>on</sub>	T <sub>j</sub> = 25 °C		tbd		μJ
Turn-Off Energy Per Pulse	$E_{off}$	Refer to Figure 15 for gate current		tbd		μJ
Total Switching Energy	$E_ts$	waveform		tbd		μJ
Turn On Delay Time	t <sub>d(on)</sub>			tbd		
Rise Time	t <sub>r</sub>	$V_{DD} = 800 \text{ V}, I_{D} = 20 \text{ A},$		tbd		ns
Turn Off Delay Time	$t_{\sf d(off)}$	$R_{G(on)} = R_{G(off)} = 44 \Omega,$ $V_{GS} = -8/15 V, L = 1.1 mH,$		tbd		ns
Fall Time	t <sub>f</sub>	FWD = GB40SLT12.		tbd		ns
Turn-On Energy Per Pulse	Eon	T <sub>j</sub> = 175 °C Refer to Figure 15 for gate current		tbd		μJ
Turn-Off Energy Per Pulse	$E_{off}$			tbd		μJ
Total Switching Energy	$E_ts$	waveform		tbd		μJ
Thermal Characteristics						
Thermal resistance, junction - case	$R_{thJC}$			0.53		°C/W

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TBD

TBD

Figure 1: Typical Output Characteristics at 25 °C

Figure 2: Typical Output Characteristics at 125 °C



TBD

**TBD** 

Figure 3: Typical Output Characteristics at 175 °C

Figure 4: Typical Gate Source I-V Characteristics vs. Temperature

**TBD** 

TBD

Figure 5: Normalized On-Resistance and Current Gain vs. Temperature

Figure 6: Typical Blocking Characteristics

**TBD** 

TBD

Figure 7: Capacitance Characteristics

Figure 8: Capacitance Characteristics



TBD

**TBD** 

Figure 9: Typical Hard-switched Turn On Waveforms

Figure 10: Typical Hard-switched Turn Off Waveforms

TBD

Figure 11: Typical Turn On Energy Losses and Switching Times vs. Temperature

Figure 12: Typical Turn Off Energy Losses and Switching Times vs. Temperature

TBD

TBD

Figure 13: Typical Turn On Energy Losses vs. Drain Current

Figure 14: Typical Turn Off Energy Losses vs. Drain Current



**TBD** 

TBD

Figure 15: Typical Gate Current Waveform

Figure 16: Typical Hard Switched Device Power Loss vs. Switching Frequency <sup>1</sup>

**TBD** 

TBD

Figure 17: Power Derating Curve

Figure 18: Forward Bias Safe Operating Area

TBD

TBD

Figure 19: Turn-Off Safe Operating Area

Figure 20: Transient Thermal Impedance

<sup>1 –</sup> Representative values based on device switching energy loss. Actual losses will depend on gate drive conditions, device load, and circuit topology.



### **Gate Drive Technique (Option #1)**

To drive the GA20JT12-247 with the lowest gate drive losses, please refer to the dual voltage source gate drive configuration described in Application Note AN-10B (http://www.genesicsemi.com/index.php/references/notes).

## **Gate Drive Technique (Option #2)**

The GA20JT12-247 can be effectively driven using the IXYS IXDN614 / IXDD614 non-inverting gate driver IC or a comparable product. A typical gate driver configuration along with component values using this driver is offered below. Additional information is available in GeneSiC Application Note AN-10A and from the manufacturer at www.ixys.com.

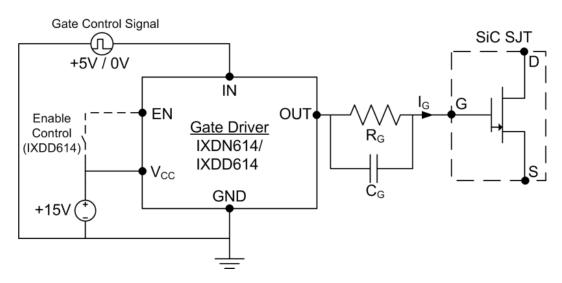
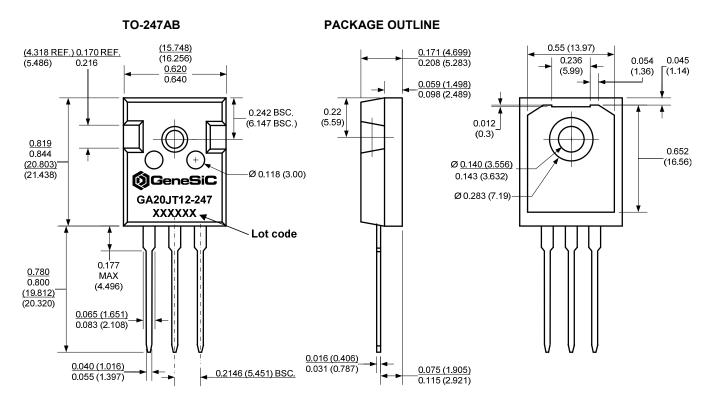


Figure 21: Recommended Gate Diver Configuration (Option #2)

Dozemster	Cumbal	Conditions	Values			11:4
Parameter	Symbol		min.	typ.	max.	Unit
Option #2 Gate Drive Conditions (I)	(DD614/IXDN614)					
Supply Voltage	V <sub>CC</sub>		-0.3	15	40	V
Gate Control Input Signal, Low	IN		-5.0	0	0.8	V
Gate Control Input Signal, High	IN		3.0	5.0	V <sub>CC</sub> +0.3	V
Enable, Low	EN	IXDD614 Only			1/3*V <sub>CC</sub>	V
Enable, High	EN	IXDD614 Only	2/3*V <sub>cc</sub>			V
Output Voltage, Low	$V_{OUT}$				0.025	V
Output Voltage, High	$V_{OUT}$		V <sub>CC</sub> -0.025			V
Output Current, Peak	I <sub>OUT</sub>	Package Limited		tbd	14	Α
Output Current, Continuous	I <sub>out</sub>			tbd	4.0	Α
Passive Gate Components						
Gate Resistance	$R_G$	I <sub>G</sub> ≈ 0.5 A	5	tbd		Ω
Gate Capacitance	C <sub>G</sub>	I <sub>G</sub> ≈ 0.5 A		tbd		nF



## **Package Dimensions:**



#### NOTE

- 1. CONTROLLED DIMENSION IS INCH. DIMENSION IN BRACKET IS MILLIMETER.
- 2. DIMENSIONS DO NOT INCLUDE END FLASH, MOLD FLASH, MATERIAL PROTRUSIONS

Revision History						
Date Revision Comments Supersedes						
2013/09/12 0 Initial release						

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## **SPICE Model Parameters**

Copy the following code into a SPICE software program for simulation of the GA20JT12 SJT device.

```
MODEL OF GeneSiC Semiconductor Inc.
     $Revision: 1.0
     $Date: 26-AUG-2013
    GeneSiC Semiconductor Inc.
    43670 Trade Center Place Ste. 155
    Dulles, VA 20166
    http://www.genesicsemi.com/index.php/sic-products/sjt
    COPYRIGHT (C) 2013 GeneSiC Semiconductor Inc.
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* These models are provided "AS IS, WHERE IS, AND WITH NO WARRANTY
* OF ANY KIND EITHER EXPRESSED OR IMPLIED, INCLUDING BUT NOT LIMITED
* TO ANY IMPLIED WARRANTIES OF MERCHANTABILITY AND FITNESS FOR A
* PARTICULAR PURPOSE."
* Models accurate up to 2 times rated drain current.
.model GA20JT12 NPN
+ IS
         5.00E-47
+ ISE
         1.26E-28
+ EG
          3.2
+ BF
         100
+ BR
         0.55
         700
+ IKF
+ NF
         1
+ NE
         0.26
+ RB
+ RC
         0.055
+ CJC
        6.98E-10
+ VJC
         3
         0.5
+ MJC
+ CJE
         2.22E-9
+ VJE
         3
+ MJE
         0.5
+ XTI
          -1.2
+ XTB
+ TRC1
         7.00E-3
+ VCEO
          1200
+ ICRATING 20
+ MFG
      GeneSiC_Semiconductor
```

\* End of GA20JT12 SPICE Model